

RF EXPOSURE REPORT

Report Number. : 11888671-E2V2

- Applicant : VALVE CORPORATION 10400 NE 4th ST. SUITE 1400 BELLEVUE, WA 98004, U.S.A.
 - **Model :** 1004
 - FCC ID : 2AES41004
 - IC : 20207-1004
- EUT Description : SteamVR Tracking 2.0 Base Station
- Test Standard(s) : FCC Part 1 Subpart I FCC Part 2 Subpart J INDUSTRY CANADA RSS 102 ISSUE 5

Date Of Issue: November 29, 2017

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RF EXPOSURE REPORT



FOR

Revision History

Rev.	Issue Date	Revisions	Revised By
V1	11/10/2017	Initial Issue	
V2	11/29/2017	Updated reference report number on Section 3	Tina Chu

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1. ATTESTATION OF TEST RESULTS

FCC PART 1 SUBPART I & PART 2 SUBPART J

INDUSTRY CANADA RSS 102 ISSUE 5

COMPANY NAME:	VALVE CORPORATION 10400 NE 4 th ST. SUITE 1400 BELLEVUE, WA 98004, U.S.A.					
EUT DESCRIPTION:	SteamVR Tracking 2.0 Base Station					
MODEL:	1004					
SERIAL NUMBER:	AB73700187 (Conducted)					
DATE TESTED:	OCTOBER 13, 2017 – OCTOBER 20, 2	017				
APPLICABLE STANDARDS						
STANDARD TEST RESULTS						

UL Verification Services Inc. calculated the RF Exposure of the above equipment in accordance with the requirements set forth in the above standards, using test results reported in the test report documents referenced below and/or documentation furnished by the applicant. All indications of Pass/Fail in this report are opinions expressed by UL Verification Services Inc. based on interpretations of these calculations. The results show that the equipment is capable of demonstrating compliance with the requirements as documented in this report.

Note: The results documented in this report apply only to the tested sample, under the conditions and modes of operation as described herein. This document may not be altered or revised in any way unless done so by UL Verification Services Inc. and all revisions are duly noted in the revisions section. Any alteration of this document not carried out by UL Verification Services Inc. will constitute fraud and shall nullify the document. This report must not be used by the client to claim product certification, approval, or endorsement by NVLAP, NIST, or any agency of the U.S. Government.

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2. TEST METHODOLOGY

All calculations were made in accordance with FCC OET Bulletin 65 Edition 97-01 and IC Safety Code 6.

3. REFERENCES

All measurements were made as documented in test report UL Verification Services Inc. Document 11888671-E1V2 for operation in the 2.4 GHz band.

Output power, Duty cycle and Antenna gain data is excerpted from the applicable test reports.

4. FACILITIES AND ACCREDITATION

The test sites and measurement facilities used to collect data are located at 47173 Benicia Street, Fremont, California, USA.

UL Verification Services Inc. is accredited by NVLAP, Laboratory Code 200065-0. The full scope of accreditation can be viewed at <u>http://ts.nist.gov/standards/scopes/2000650.htm</u>.

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5. MAXIMUM PERMISSIBLE RF EXPOSURE

5.1. FCC RULES

§1.1310 The criteria listed in Table 1 shall be used to evaluate the environmental impact of human exposure to radio-frequency (RF) radiation as specified in §1.1307(b), except in the case of portable devices which shall be evaluated according to the provisions of §2.1093 of this chapter.

Frequency range (MHz)	Electric field strength (V/m)	Magnetic field strength (A/m)	Power density (mW/cm ²)	Averaging time (minutes)
	(A) Limits for Oc	cupational/Controlled Ex	posure	
0.3-3.0	614	1.63	*100	6
3.0-30	1842/f	4.89/f	*900/f ²	6
30-300	61.4	0.163	1.0	6
300-1,500			f/300	6
1,500-100,000			5	6
	(B) Limits for Genera	I Population/Uncontrolle	d Exposure	
0.3-1.34	614	1.63	*100	30
1.34-30	824/f	2.19/f	*180/f ²	30
30-300	27.5	0.073	0.2	30
300-1,500			f/1500	30
1,500-100,000			1.0	30

TABLE 1—LIMITS FOR MAXIMUM PERMISSIBLE EXPOSURE (MPE)

f = frequency in MHz

* = Plane-wave equivalent power density

Notes:

- (1) Occupational/controlled exposure limits apply in situations in which persons are exposed as a consequence of their employment provided those persons are fully aware of the potential for exposure and can exercise control over their exposure. Limits for occupational/controlled exposure also apply in situations when a person is transient through a location where occupational/controlled limits apply provided he or she is made aware of the potential for exposure.
- (2) General population/uncontrolled exposure limits apply in situations in which the general public may be exposed, or in which persons who are exposed as a consequence of their employment may not be fully aware of the potential for exposure or cannot exercise control over their exposure

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5.2. IC RULES

IC Safety Code 6 (2015), Section 2.2.2: To ensure compliance with the basic restrictions outlined in Section 2.1, at frequencies between 10 MHz and 300 GHz, the reference levels for electric- and magnetic-field strength and power density must be complied with.

TABLE 5: Reference Levels for Electric Field Strength, Magnetic Field Strength and Power Density in Uncontrolled Environments

Frequency (MHz)	Electric Field Strength (E _{st}), (V/m, RMS)	Magnetic Field Strength (H _{RL}), (A/m, RMS)	Power Density (S _{RL}), (W/m²)	Reference Period (minutes)	
10-20	27.46	0.0728	2	6	
20-48	58.07 / f 0.25	0.1540 / f 0.25	8.944 / f °5	6	
48-300	22.06	0.05852	1.291	6	
300-6000	3.142 f 0.3417	0.008335 f 0.3417	0.02619 f 0.6834	6	
6000-15000	61.4	0.163	10	6	
15000-150000	61.4	0.163	10	616000 / f 12	
150000-300000	0.158 f °5	4.21x10 ⁻⁴ f □5	6.67x10-⁵ f	616000 / f 12	

Frequency, f, is in MHz.

TABLE 6: Reference Levels for Electric Field Strength, Magnetic Field Strength and Power Density in Controlled Environments

Frequency (MHz)	Electric Field Strength (E _{st.}), (V/m, RMS)	Magnetic Field Strength (H _{at}), (A/m, RMS)	Power Density, (S _{RL}), (W/m²)	Reference Period (minutes)	
10-20	61.4	0.163	10	6	
20-48	129.8 / f 0.25	0.3444 / f 025	44.72 / f °5	6	
48-100	49.33	0.1309	6.455	6	
100-6000	15.60 f 0.25	0.04138 f 025	0.6455 f °5	6	
6000-15000	137	0.364	50	6	
15000-150000	137	0.364	50	616000 / f 12	
150000-300000	0.354 f °	9.40x10 ⁻⁴ f □=	3.33x10-4 f	616000 / f 12	

Frequency, f, Is In MHz.

NOTES FOR TABLES 5 AND 6:

1. For exposures shorter than the reference period, field strengths may exceed the reference levels, provided that the time average of the squared value of the electric or magnetic field strength over any time period equal to the reference period shall not exceed E_{RL}^{2} or H_{RL}^{2} , respectively. For exposures longer than the reference period, including indefinite exposures, the time average of the squared value of the electric or magnetic field strength over any time period equal to the reference period, including indefinite exposures, the time average of the squared value of the electric or magnetic field strength over any time period equal to the reference period shall not exceed E_{RL}^{2} or H_{RL}^{2} , respectively.

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5.3. EQUATIONS

POWER DENSITY

Power density is given by:

S = EIRP / (4 * Pi * D^2)

Where

S = Power density in mW/cm² EIRP = Equivalent Isotropic Radiated Power in mW D = Separation distance in cm

Power density in units of mW/cm² is converted to units of W/m² by multiplying by 10.

DISTANCE

Distance is given by:

D = SQRT (EIRP / (4 * Pi * S))

Where

D = Separation distance in cm EIRP = Equivalent Isotropic Radiated Power in mW S = Power density in mW/cm^2

SOURCE-BASED DUTY CYCLE

Where applicable (for example, multi-slot cell phone applications) a duty cycle factor may be applied.

Source-based time-averaged EIRP = (DC / 100) * EIRP

Where

DC = Duty Cycle in %, as applicable EIRP = Equivalent Isotropic Radiated Power in W

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MIMO AND COLOCATED TRANSMITTERS (IDENTICAL LIMIT FOR ALL TRANSMITTERS)

For multiple chain devices, and colocated transmitters operating simultaneously in frequency bands where the limit is identical, the total power density is calculated using the total EIRP obtained by summing the EIRP (in linear units) of each transmitter.

Total EIRP = (EIRP1) + (EIRP2) + ... + (EIRPn)

where

EIRPx = Source-based time-averaged EIRP of chain x or transmitter x

The total EIRP is then used to calculate the Power Density or the Distance as applicable.

MIMO AND COLOCATED TRANSMITTERS

For multiple colocated transmitters operating simultaneously in frequency bands where different limits apply:

The Power Density at the specified separation distance is calculated for each transmitter chain or transmitter.

The fraction of the exposure limit is calculated for each chain or transmitter as (Power Density of chain or transmitter) / (Limit applicable to that chain or transmitter).

The fractions are summed.

Compliance is established if the sum of the fractions is less than or equal to one.

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5.4. IC EXEMPTION

VARIABLE LIMITS

For mobile radio equipment operating in the cellular phone band, the lowest power density limit is calculated using the lowest frequency:

2402 MHz / 1500 = 1.6 mW/cm² (FCC) S = 0.02619 $f^{0.6834}$ W/m² (IC).

FIXED LIMITS

For operation in the PCS band, the 2.4 GHz band and the 5 GHz bands:

From FCC §1.1310 Table 1 (B), the maximum value of S = 1.0 mW/cm² From IC Safety Code 6, Section 4 Table 4 Column 4, S = $0.02619 f^{0.6834}$ W/m²

INDUSTRY CANADA EXEMPTION

RF exposure evaluation is required if the separation distance between the user and/or bystander and the device's radiating element is greater than 20 cm, except when the device operates as follows:

- below 20 MHz and the source-based, time-averaged maximum e.i.r.p. of the device is equal to or less than 1 W (adjusted for tune-up tolerance);
- at or above 20 MHz and below 48 MHz and the source-based, time-averaged maximum e.i.r.p. of the device is equal to or less than 4.49/f0.5 W (adjusted for tune-up tolerance), where *f* is in MHz;
- at or above 48 MHz and below 300 MHz and the source-based, time-averaged maximum e.i.r.p. of the device is equal to or less than 0.6 W (adjusted for tune-up tolerance);
- at or above 300 MHz and below 6 GHz and the source-based, time-averaged maximum e.i.r.p. of the device is equal to or less than 1.31 x 10-2 *f* 0.6834 W (adjusted for tune-up tolerance), where *f* is in MHz;
- at or above 6 GHz and the source-based, time-averaged maximum e.i.r.p. of the device is equal to or less than 5 W (adjusted for tune-up tolerance).

In these cases, the information contained in the RF exposure technical brief may be limited to information that demonstrates how the e.i.r.p. was derived.

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6. RF EXPOSURE RESULTS

In the table(s) below, Power and Gain are entered in units of dBm and dBi respectively and conversions to linear forms are used for the calculations.

(Single chain transmitters, no colocation, 20 cm MPE distance)

Single Chain and non-colocated transmitters								
Band	Mode	Separatio	Output	Antenna	Duty	EIRP	FCC Power IC	
		Distance	AVG	Gain	Cycle		Density	Density
			Power					
		(cm)	(dBm)	(dBi)	(%)	(mW)	(mW/cm^2)	(W/m^2)
2.4 GHz	BLE	20	0.36	6.80	100.0	5.2	0.001	0.01

Notes:

- 1) The manufacturer configures output power so that the maximum power, after accounting for manufacturing tolerances, will never exceed the maximum power level measured.
- 2) The output power in the tables above is the maximum power among various channels and various modes within the specific band.
- 3) The antenna gain in the tables above is the maximum antenna gain among various channels within the specified band.
- 4) 100% duty cycle was used in the calculation as worst-case scenario.

END OF REPORT

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